

<b>Notice of References Cited</b>	Application/Control No. 10/617,027	Applicant(s)/Patent Under Reexamination KIM ET AL.	
	Examiner Sheela C. Chawan	Art Unit 2624	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,334,847 B1	01-2002	Fenster et al.	600/443
	B	US-5,454,371	10-1995	Fenster et al.	600/443
	C	US-6,444,192 B1	09-2002	Mattrey, Robert F.	424/9.52
	D	US-6,106,466	08-2000	Sheehan et al.	600/443
	E	US-7,123,762 B2	10-2006	Giger et al.	382/132
	F	US-6,549,646 B1	04-2003	Yeh et al.	382/132
	G	US-6,366,687 B1	04-2002	Aloni et al.	382/144
	H	US-6,461,298 B1	10-2002	Fenster et al.	600/437
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.